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Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022 Based on structural similarity

Supplier		User Part Number				
Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		PZU4.3B3A-Q Part Description				
		SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects
			TEST			
	Pre- and Post-Stress					
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
		JESD22-A113				
		Bake Tamb = 125 °C	24 hours			
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours			
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0
		MIL-STD-750-1				
	HTRB	M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse				
# B1	Bias	voltage	1000 hours	198	11960	0
# D1	Dias	5	1000 110015	196	11900	0
		MIL-STD-750-1 M1038 Method B				
	SSOP	$T_j = T_j max$, $I_z = 100\%$ of max. datasheet				
# B1b	Steady State Operational	reverse current	1000 hours	24	1760	0
. 010			1000 110010		1,00	0
	тс	JESD22-A104				
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	240	14800	0
	UHAST	JESD22-A118				
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	96 hours	240	14800	0
		JESD22-A102				
	AC	Tamb = 121 °C, RH = 100 %				
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)				
	H3TRB	JESD22-A101				
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of				
# A2 alt	Temperature Reverse Bias	rated reverse voltage ^[1]	1000 hours	240	14800	0
		MIL-STD-750 Method 1037				
" • -	IOL	ton = toff, devices powered to insure ΔT_j =	1000	264	4 6 7 9 9	
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	264	16720	0
	рсц	JECD22 A111				
# C8	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	184	5520	0
# 0	SD	200 0 - 5 0	10.5	104	5520	U
# C10	Solderability	J-STD-002		501	5010	0
# CIU	Solderability	5 510 002		201	2010	U

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

2,82E+09

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